

LIST OF ART CITED BY APPLICANT (PTO-1449)			ATTY. DOCKET NO. K-0196A		APPLN. SERIAL NO. 10/720,385	
			APPLICANT(S) Jae Sung KIM, Chung Huan JEON, Eun Cheol LEE, Young Joon AHN, Seok Dong KANG and Sung Yong AHN			
			FILING DATE November 25, 2003		GROUP 2879	
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
	5,674,553	10/07/1997	Shinoda et al.	427	68	06/02/1995
	6,433,477 B1	08/13/2002	Ha et al.	313	586	10/22/1998
U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
						Yes
	JP 09-237580	09/09/1997	Japan (English Abstract and Japanese Full Text)			X
	JP 10-228858	08/25/1998	Japan (English Abstract and Japanese Full Text)			X
	JP 11-067099	03/09/1999	Japan (English Abstract and Japanese Full Text)			X
	JP 10-283934	10/23/1998	Japan (English Abstract and Japanese Full Text)			X
	JP 10-199427	07/31/1998	Japan (English Abstract and Japanese Full Text)			X
	JP 10-308176	11/17/1998	Japan (English Abstract and Japanese Full Text)			X
	JP 10-308177	11/17/1998	Japan (English Abstract and Japanese Full Text)			X
	JP 08-077930	03/22/1996	Japan (English Abstract and Japanese Full Text)			X
	JP 09-022656	01/21/1997	Japan (English Abstract and Japanese Full Text)			X
	JP 09-129142	05/16/1997	Japan (English Abstract and Japanese Full Text)			X
	JP 09-259768	10/03/1997	Japan (English Abstract and Japanese Full Text)			X
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)						
EXAMINER	DATE CONSIDERED					

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